



# MOCVD of transition metal dichalcogenides: Hydrogen evolution reaction studies on $\text{MoS}_2$ and $\text{WS}_2$

Jan-Lucas Wree, Anjana Devi

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**Ruhr University Bochum**  
Faculty of Chemistry and Biochemistry  
Inorganic Materials Chemistry  
Germany

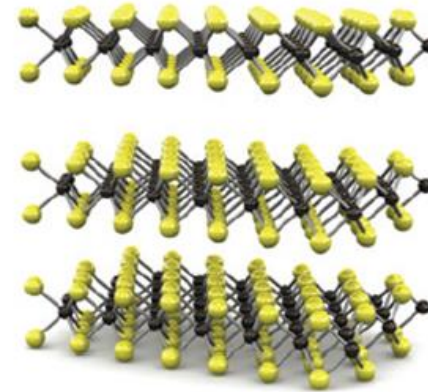
# Transition Metal Dichalcogenides (TMDs) – Properties & Applications

## Structure

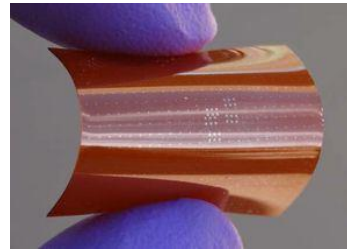
- S-M-S triple layers **stacked through vdW interactions**
- 2H, 3R, (1T) polytypes

## Properties

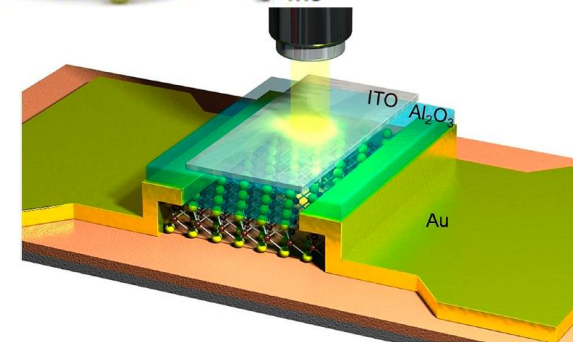
- As bulk (2H): indirect band gaps of 1.29 eV ( $\text{MoS}_2$ ) and 1.3 eV ( $\text{WS}_2$ )  
→ **n-type semiconductors**
- Indirect band gap → direct band gap of 1.8 eV ( $\text{MoS}_2$ ) and 2.1 eV ( $\text{WS}_2$ ) for monolayers
- Increased photoluminescence and absorption (NIR)
- **Flexible sheets** → 11 % deformation possible



● S  
● Mo  
B. Radisavljevic, *et al.*,  
*Nature Nanotechnology*  
**2011**, 6, 147.

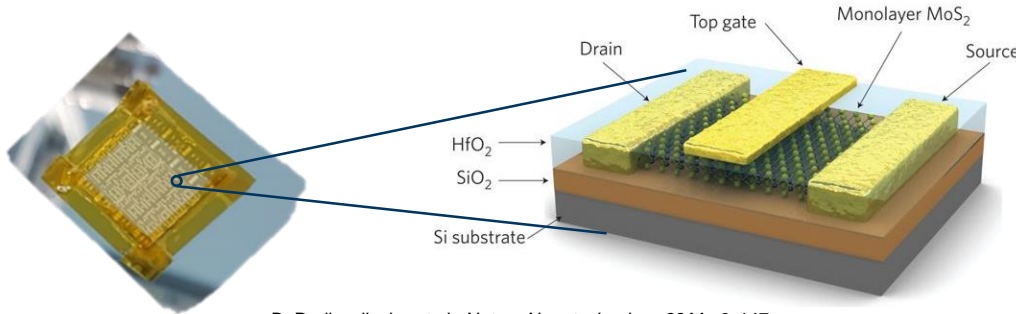


[https://www.scienceandtechnologyresearchnews.com/wp-content/uploads/2014/10/MoS2-flexible-circuit\\_thmb.jpg](https://www.scienceandtechnologyresearchnews.com/wp-content/uploads/2014/10/MoS2-flexible-circuit_thmb.jpg)



H. S. Lee, *et al.*, *Nano Lett.* **2012**, 12, 3695.

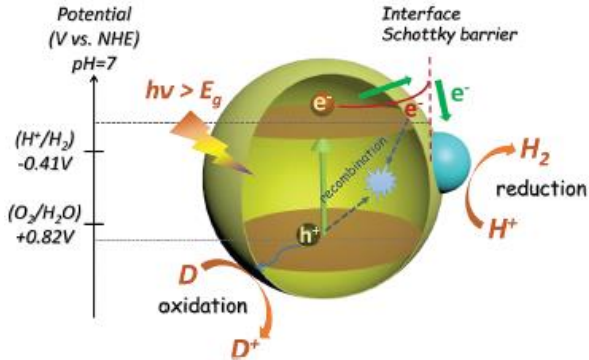
# Properties & Applications



B. Radisavljevic, *et al.*, *Nature Nanotechnology* **2011**, 6, 147.



<https://www.extox.de/de/produkte/83-transmitter/145-transmitter-exsens>



K. Chang, *et al.*, *Adv. Energy Mater.* **2016**, 6, 1502555.

## Applications

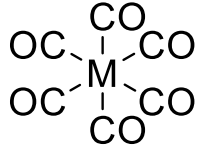
- Electronics on TFT basis (2H)
- HER (co-catalyst)
- Sensors



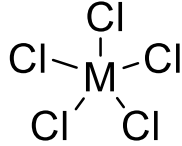
<https://www.robotshop.com/de/de/mq-135-gassensor.html>

→ CVD and ALD necessary for large-area, high uniformity and precise thickness control

# Precursor



N. Imanishi, *J. Electrochem. Soc.* **1992**, 139, 2082.



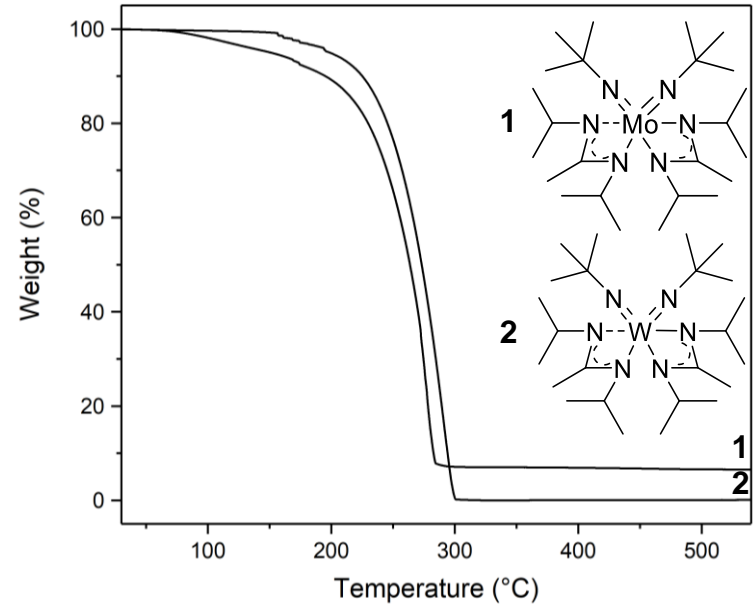
W. K. Hofmann, *J Mater Sci* **1988**, 23, 3981.

Improved



Precursors

- + Highly uniform films
- Halide incorporation
- Toxic by-products
- Usage of toxic H<sub>2</sub>S as co-reactant



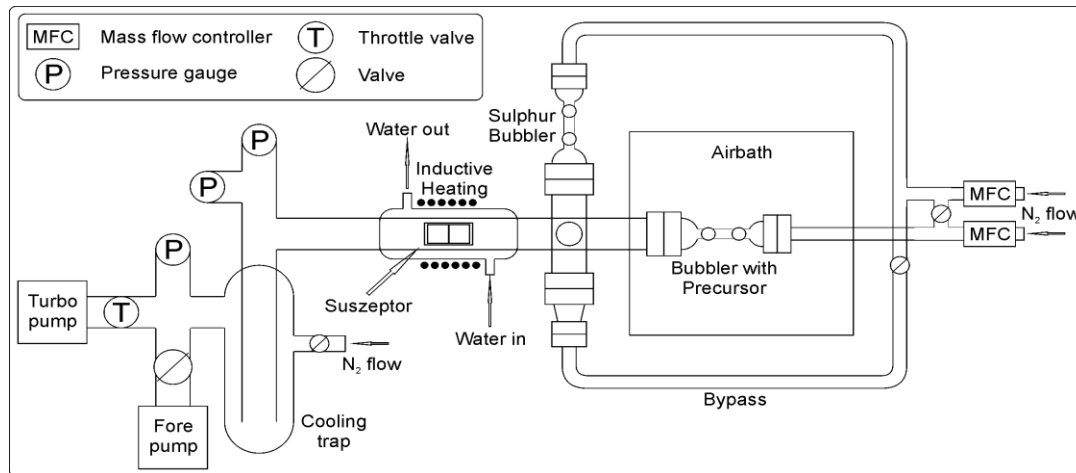
- Volatile and thermally stable
- One-step evaporation
- **Onset: 90 - 100 °C** (1 % mass loss)
- Residual masses < 10 wt. %

→ Thermal properties of the precursors promising for application in MOCVD



# MOCVD of $\text{MoS}_2$ & $\text{WS}_2$

## Reactor setup

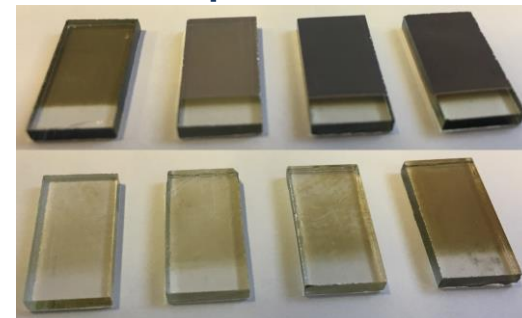


## Process parameters

- $T_{\text{evap.}} = 80\text{ }^{\circ}\text{C}$  (precursor),  $T_{\text{evap.}} = 130\text{ }^{\circ}\text{C}$  (sulfur)
- $T_{\text{dep.}}$  varied from 600 to 800  $^{\circ}\text{C}$ ,  $p = 1\text{ mbar}$
- **Direct growth of TMDs** without post deposition treatment

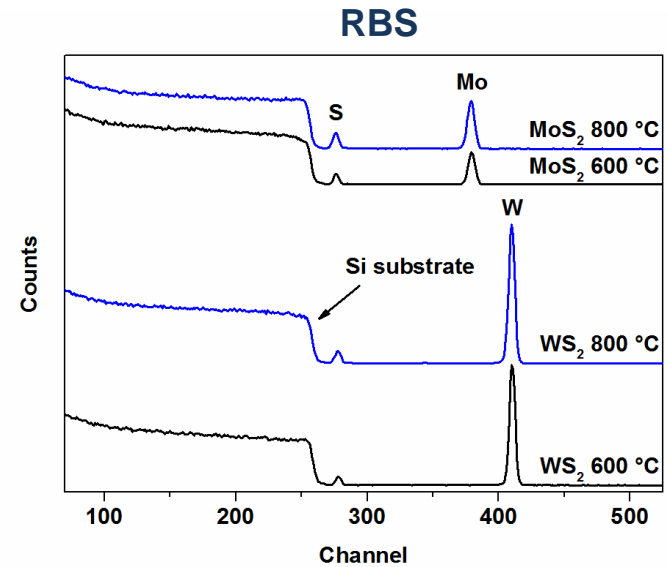


## Optical appearance of Mo and W films on quartz substrates

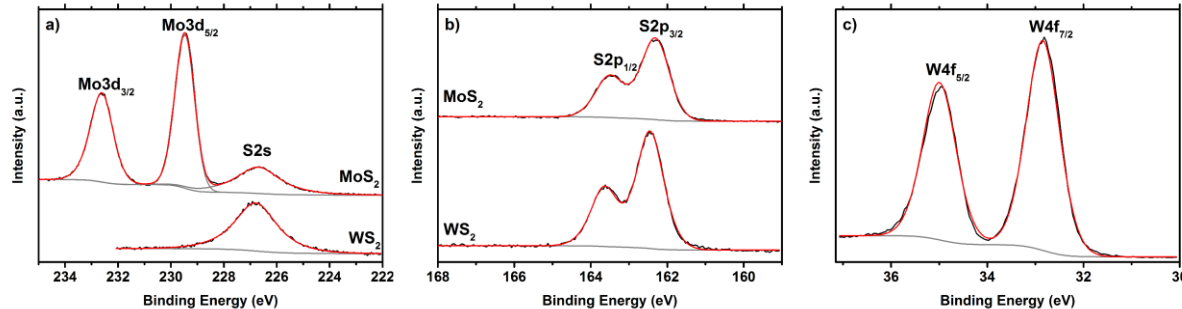


# Compositional Analysis

	M (at. %)	S (at. %)	O (at. %)	N (at. %)	C (at. %)	M/S ratio
WS <sub>2</sub> (600 °C)	29.4	46.6	0.1	17.8	6.1	0.63
WS <sub>2</sub> (800 °C)	24.3	50.1	4.0	5.2	16.5	0.48
MoS <sub>2</sub> (600 °C)	30.2	63.2	0.1	2.9	3.6	0.48
MoS <sub>2</sub> (800 °C)	30.9	60.7	3.3	0.6	4.5	0.51



## XPS

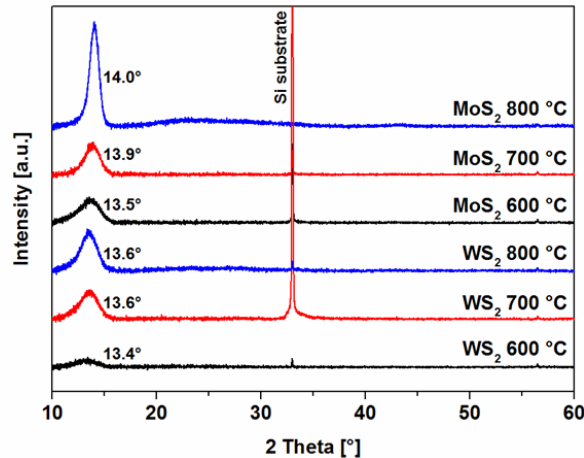


- **RBS/NRA and XPS** reveal M/S ratio of around 0.5 at 800 °C
- Mo precursor highly reactive towards elemental sulfur under adopted process conditions
- Thickness 20 nm

# Structural Analysis

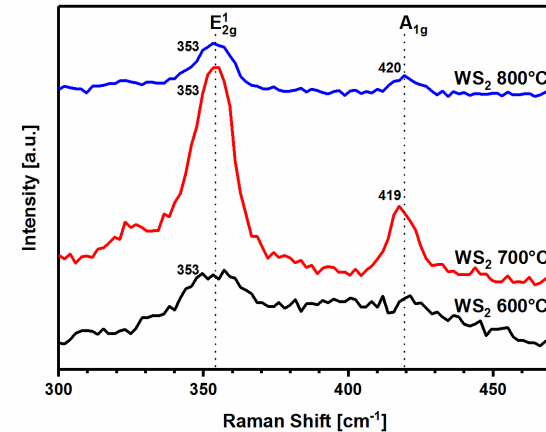
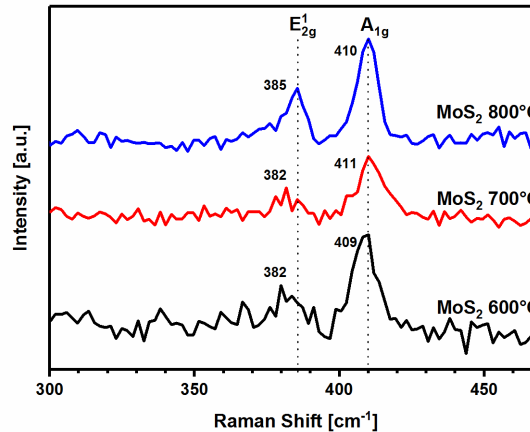
## XRD (ICSD 95570 + ICSD 202366)

- Hexagonal (2H) MoS<sub>2</sub> and WS<sub>2</sub> (P63/mmc)
- Widths of reflexes decrease with higher T → Larger crystallite size
- Reflex shift at lower T → Strain effects

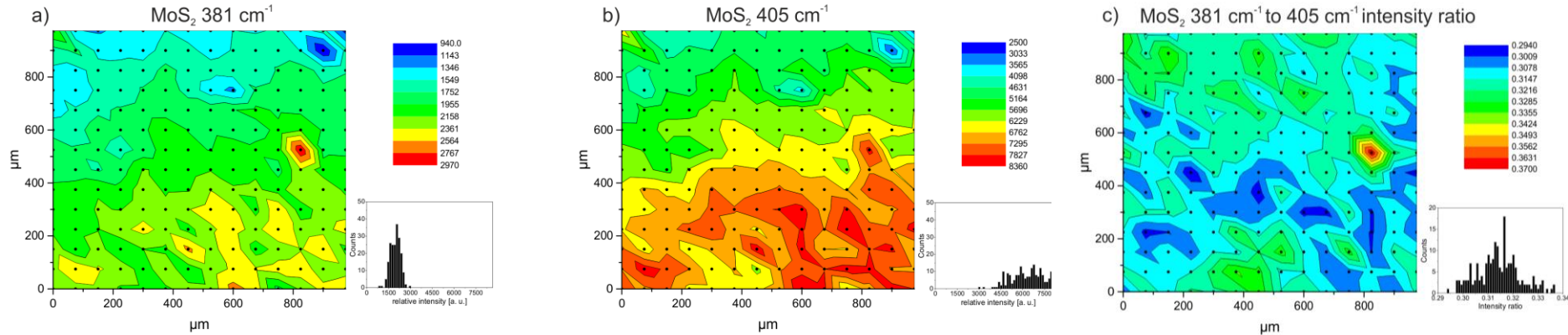


## Raman spectroscopy

- In-plane and out-of plane vibration appear
- Frequency difference as indicator for No. of layers (<20 ML for 25 cm<sup>-1</sup>)
- Increases for thicker films



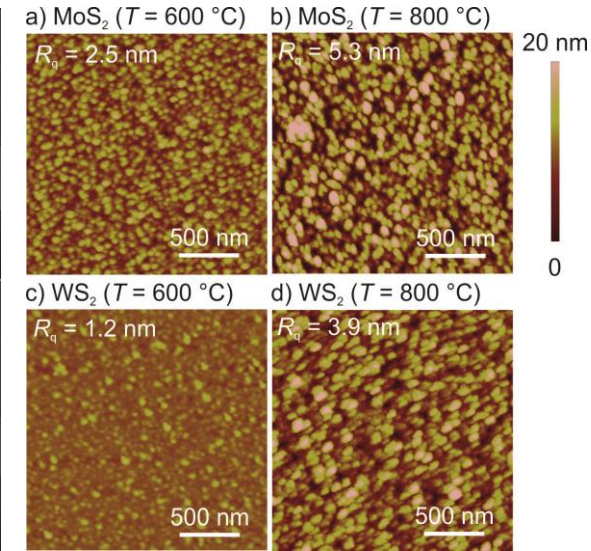
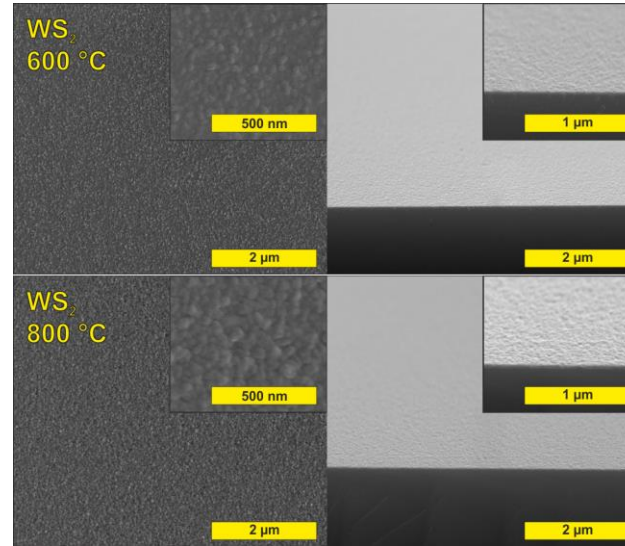
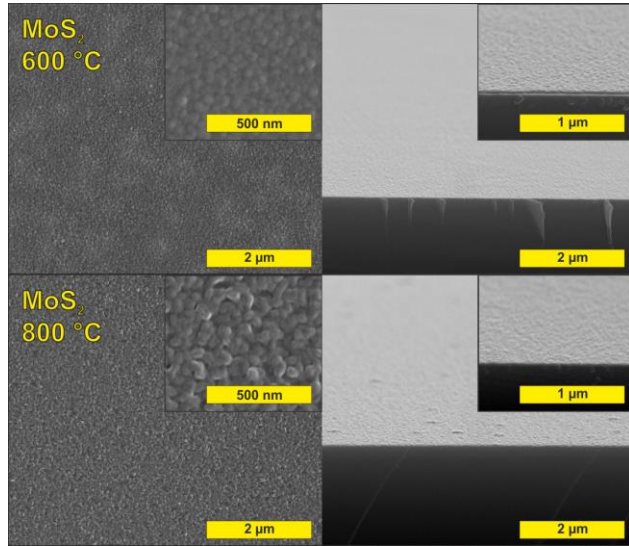
# Raman Mapping



- (1 x 1) mm<sup>2</sup> samples (step size 75 μm) of 10 nm MoS<sub>2</sub> on Si
  - Intensity of the two characteristic Raman peaks mapped (381 cm<sup>-1</sup> and 405 cm<sup>-1</sup>)
  - Narrow signals intensity ratio → **large-area uniformity**
- **XRD and Raman Mapping revealed successful fabrication of 2H structures with large area uniformity**

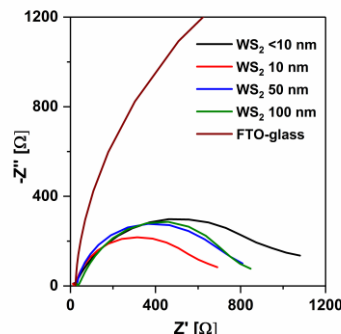
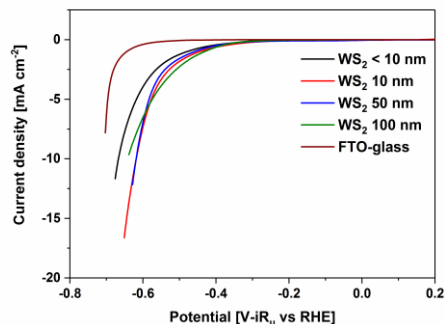
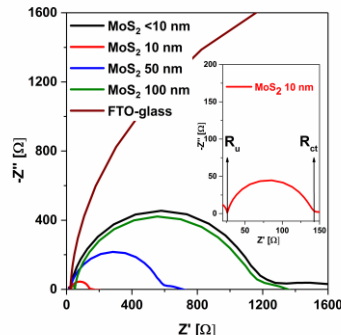
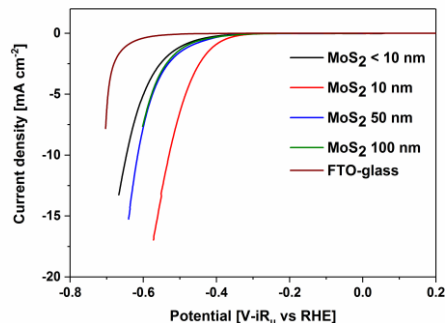


# Surface Morphology



- Large-area coverage over whole temperature range
- T-dependent crystallite formation (higher roughness of 800 °C film)
- Growth rates from cross-sections 2 nm min<sup>-1</sup> (600 °C and 800 °C) and 3 nm min<sup>-1</sup> (700 °C)

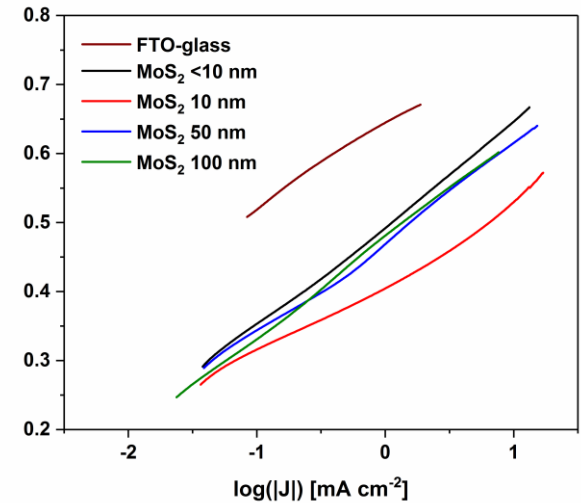
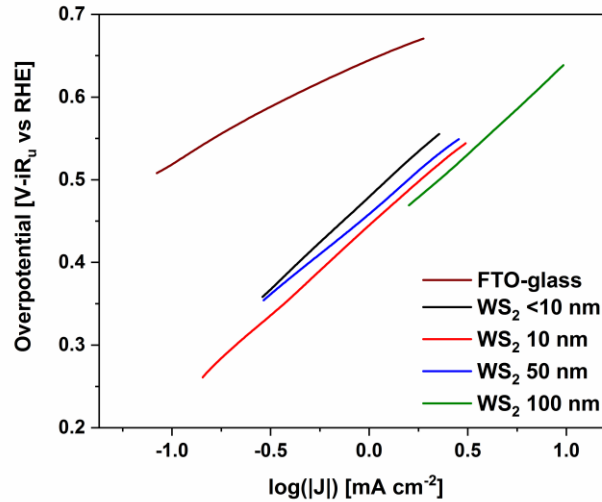
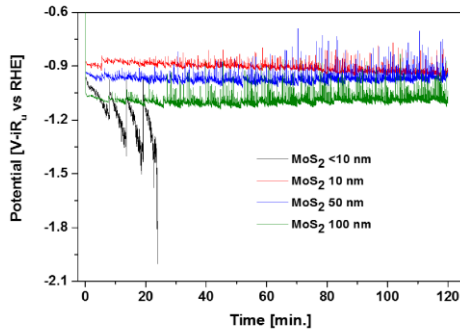
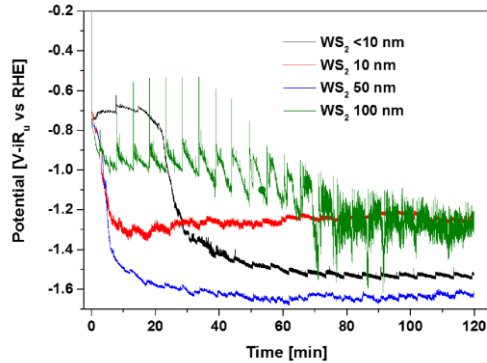
# Hydrogen Evolution Reaction (HER) Studies



- MoS<sub>2</sub> as promising electrocatalyst for HER
- Electrocat. activity of films on FTO-glass in 0.5 M H<sub>2</sub>SO<sub>4</sub>
- Polarization curves from LSV
- -0.48 V overpotential vs. RHE for 10 nm film (-5 mA cm<sup>-2</sup> current density)
- Best performing film also with lowest charge transfer resistance (Nyquist plot)
- Anisotropic activity (edge and basal planes)
- WS<sub>2</sub> films with poor performance (-0.58 V)
- Instability under reductive conditions visible in long-term galvanostatic tests

→ MoS<sub>2</sub> with better performance as co-catalyst

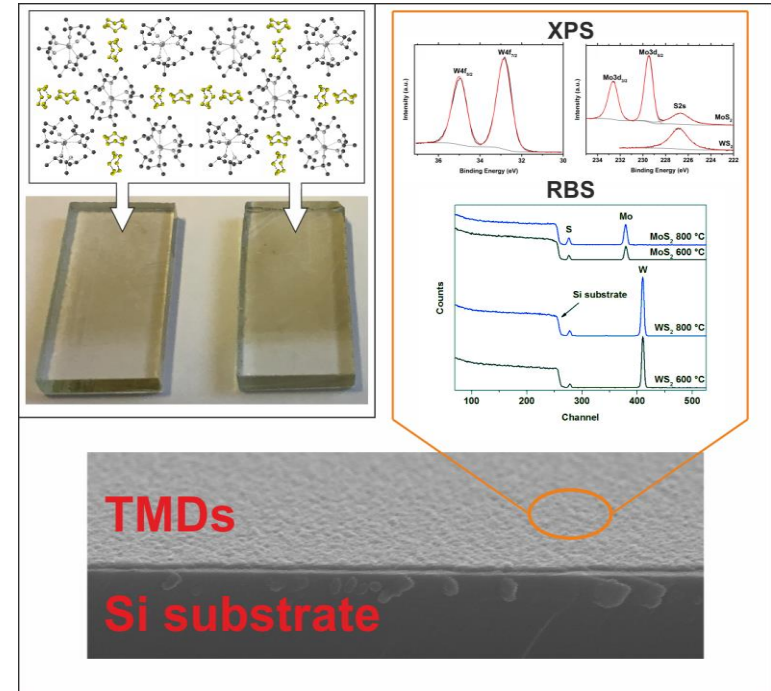
# HER Studies



- Unusual high Tafel slopes of WS<sub>2</sub> films also indicate pronounced reductive processes rather than HER
- 109 mV per decade for best performing MoS<sub>2</sub> film
- ➔ **Primary Volmer reaction step is rate-limiting for the HER**
- Low absorbance above 800 nm also advantageous

# Summary & Outlook

- New route for **direct growth of MoS<sub>2</sub> and WS<sub>2</sub> through MOCVD with elemental sulfur**
  - **No post-deposition treatment needed**
  - **Large-area uniform films** with low level of impurities
  - Promising film quality especially for MoS<sub>2</sub> films
  - Good performance in HER activity tests
- 
- Further precursor screening concerning reactivity towards less harmful sulfur sources like elemental sulfur
  - Gas sensor tests under preparation
  - Investigation of electric properties and evaluation as channel material in TFTs
  - Transfer to ALD for better thickness control (ML growth)



S. Cwik, et al., *Adv. Mater. Interfaces* **2018**, 5, 1800140.

# Thank you for your attention



Gesellschaft  
Deutscher  
Chemiker (GDCh)

Dr. Stefan Cwik

**DFG** Deutsche  
Forschungsgemeinschaft  
German Research Foundation



We launched a twitter bot:

**CVD/ALD Papers**

**(@CVD\_ALD\_papers)**

Surveying and tweeting recent publications featuring  
CVD/ALD/MLD

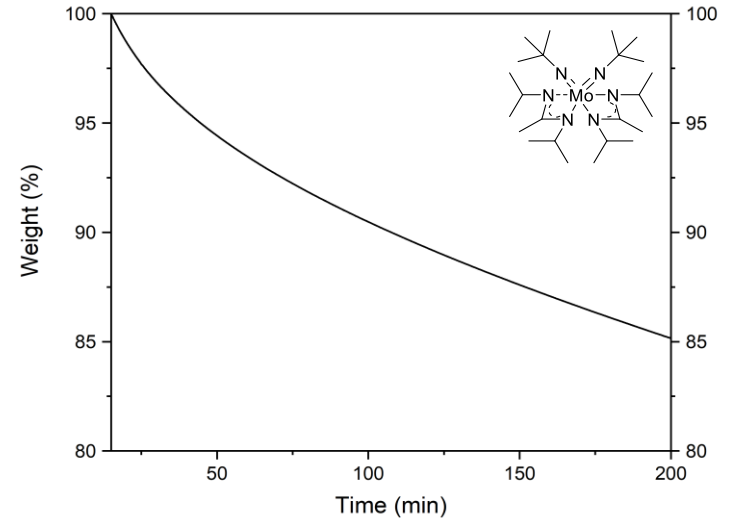
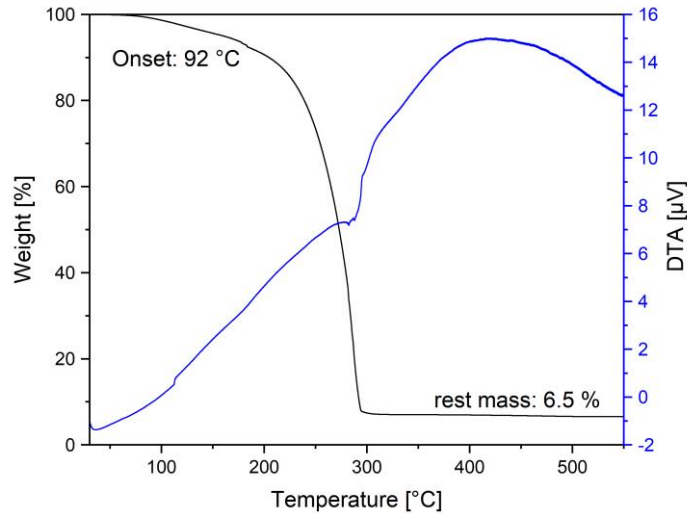
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# Appendix

## DTA and Iso-TG

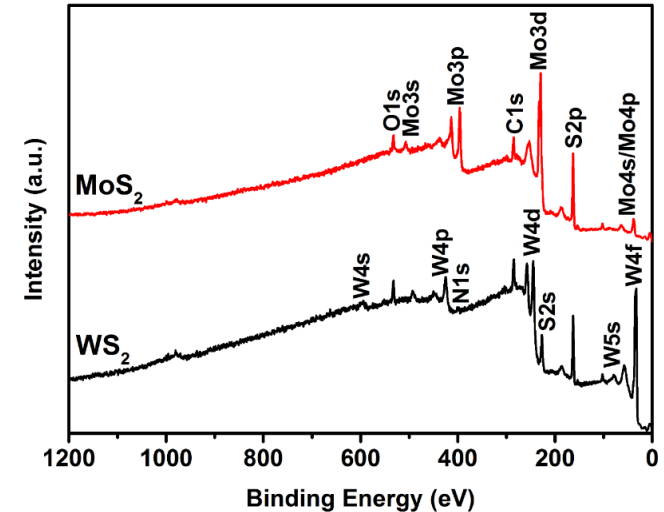
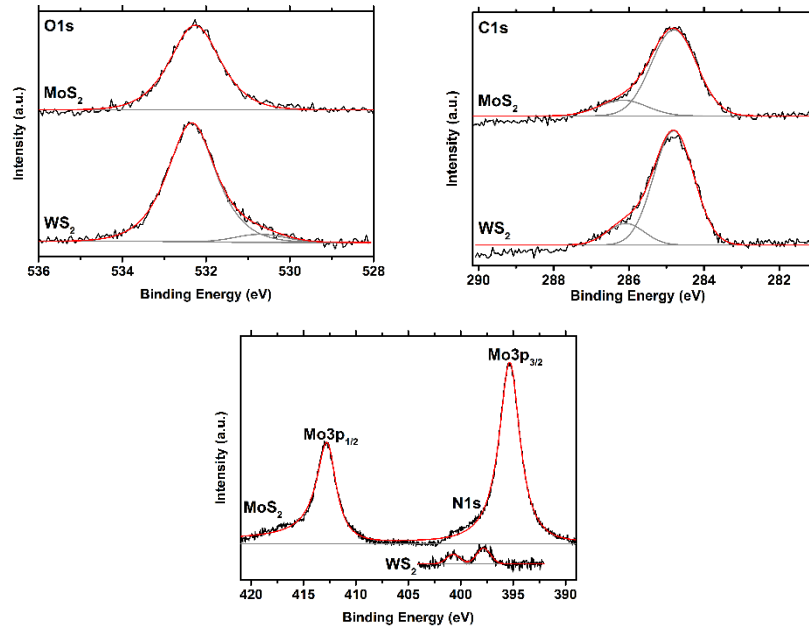


- Iso-TGA at 80 °C, 200 min
- Evaporation rate: 13 μg/min
- Linear evaporation

→ Constant evaporation without decomposition at 80 °C

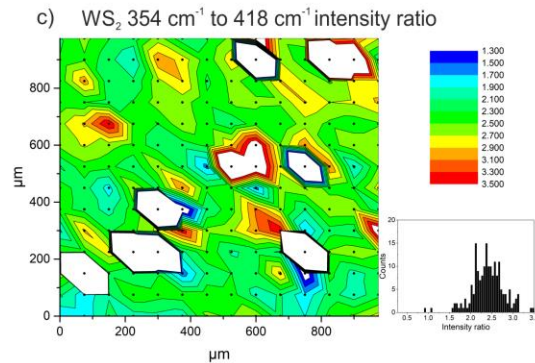
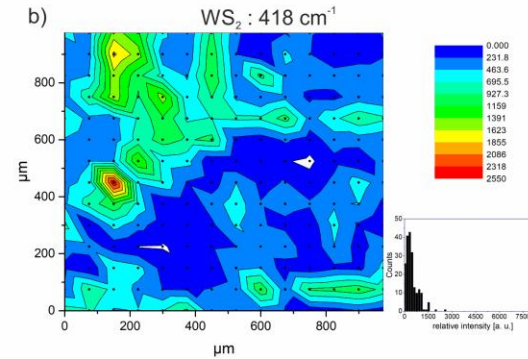
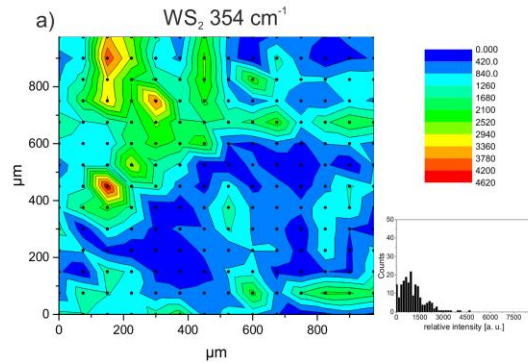
# Appendix

## XPS

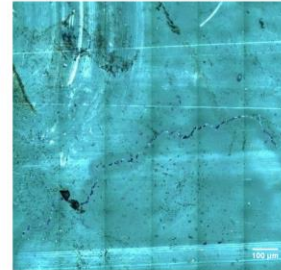


# Appendix

## Raman Mapping

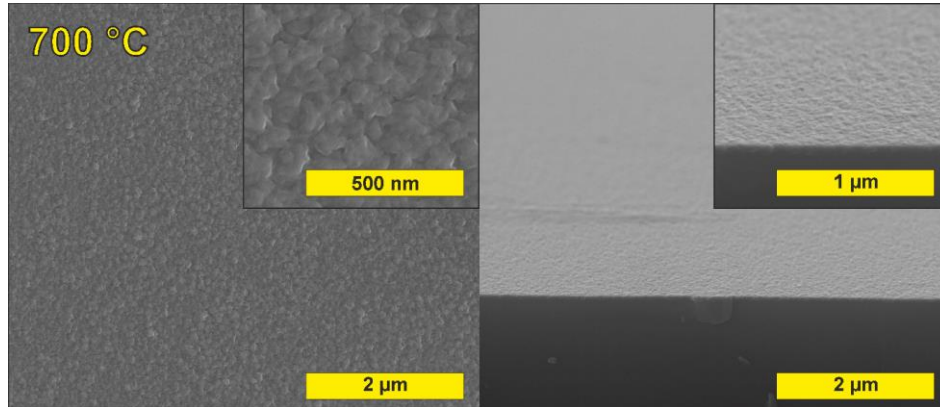
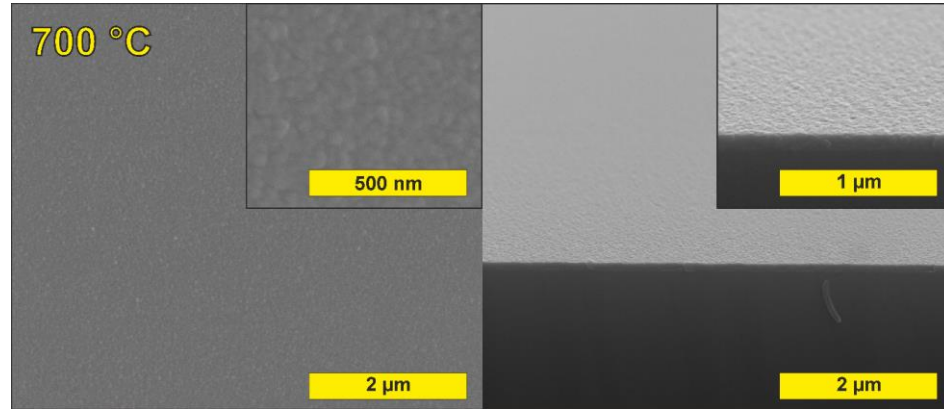


d) Image of  $\text{WS}_2$  mapping surface



# Appendix

SEM



# Appendix

## Absorbance

